



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

100725-00040

SERIAL NO.

09/853,038

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

WATANABE et al.

FILING DATE

May 11, 2001

GROUP

3679

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION		
							YES	NO	PART.
	AG	11-210776	08/03/1999	JP				X	
	AH	60-53220	03/26/1985	JP				X	
	AI	2001-32850	02/06/2001	JP				X	
	AJ								
	AK								
	AL								

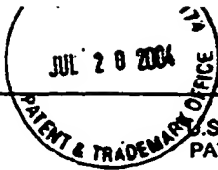
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AM	
	AN	
	AO	

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DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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	AH	55-017765	07/02/1980	JP					X
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